CLAIMS

[Claim 1] A probe comprising a probe tip portion, a probe middle portion, and a probe base portion that contact an inspection object,

wherein the probe middle portion and the probe base portion comprising:

a support structure body that is at least partially insulated from the electrical path extending from a tester to the probe tip portion,

an electrical path structure body that forms part of the electrical path extending from the tester to the probe tip portion, and

a resistor portion having a predetermined resistance value is provided in series to the electric path of the electric path structural body.

[Claim 2] The probe according to claim 1, wherein an insulating portion is provided between the support structure body and the electrical path structure body to insulate the support structure body from the electrical path structure body.

[Claim 3] The probe according to claim 1, wherein a space is provided between the support structural body and the electric path structural body.

[Claim 4] The probe according to any one of claim 1 to 3, wherein the probe is formed in a flat plate and the support structural body and the electric path structural body are formed on the same plane.

[Claim 5] The probe according to any one of claim 1 to 4, wherein at least a part of the probe middle portion of the support structural body has an insulating portion, and the

probe base portion of the support structural body is electrically connected to the electric path structural body.

[Claim 6] The probe according to any one of claim 1 to 3, wherein the support structural body and the electric path structural body are formed on different planes.

[Claim 7] The probe according to claim 6, wherein
an insulating layer is provided on a surface of the support structural body, and
the electric path structural body is provided on a surface on the insulating layer.

[Claim 8] The probe according to claim 6, wherein an insulating coat is provided between a probe middle portion and the probe base portion of the support structural body, and insulation is provided therebetween by using the insulating coat.

[Claim 9] The probe according to claim 7, wherein
the electric path structural body is a conductive path connecting a probe middle portion and the probe base portion of the support structural body through a resistance wiring layer that is insulating part of the electric path structural body which is provided on a surface of the insulating layer provided on the surface of the support structural body.

[Claim 10] The probe according to claim 7, wherein the electric path structural body is connected to a leg protruding from the probe base portion.

[Claim 11] The probe according to claim 10, wherein the probe is a cantilever type probe, and a direction in which the leg protrudes and a direction in which the probe tip

portion of the probe protrudes from the probe middle portion are the same.